

<b>Notice of References Cited</b>	Application/Control No. 10/531,697	Applicant(s)/Patent Under Reexamination YAMAKAWA ET AL.	
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*	B	US-7,160,487	01-2007	Miura, Shuichi	252/500
*	C	US-7,115,218	10-2006	Kydd et al.	252/512
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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